

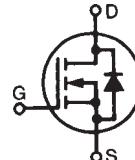
PolarHT™ HiPerFET IXFR 102N30P Power MOSFET

(Electrically Isolated Back Surface)

N-Channel Enhancement Mode

Fast Intrinsic Diode

Avalanche Rated

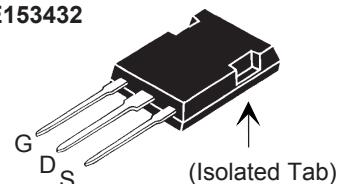


V_{DSS} = 300 V
 I_{D25} = 60 A
 $R_{DS(on)}$ ≤ 36 mΩ
 t_{rr} ≤ 200 ns

Symbol	Test Conditions	Maximum Ratings		
V_{DSS}	T_J = 25°C to 150°C	300	V	
V_{DGR}	T_J = 25°C to 150°C; $R_{GS} = 1\text{ M}\Omega$	300	V	
V_{GS}	Continuous	±20	V	
V_{GSM}	Transient	±30	V	
I_{D25}	T_c = 25°C	60	A	
I_{DM}	T_c = 25°C, pulse width limited by T_{JM}	250	A	
I_{AR}	T_c = 25°C	60	A	
E_{AR}	T_c = 25°C	60	mJ	
E_{AS}	T_c = 25°C	2.5	J	
dv/dt	$I_s \leq I_{DM}$, $di/dt \leq 100\text{ A}/\mu\text{s}$, $V_{DD} \leq V_{DSS}$, $T_J \leq 150^\circ\text{C}$, $R_G = 4\text{ }\Omega$	10	V/ns	
P_D	T_c = 25°C	250	W	
T_J		-55 ... +150	°C	
T_{JM}		150	°C	
T_{stg}		-55 ... +150	°C	
T_L	1.6 mm (0.062 in.) from case for 10 s	300	°C	
V_{ISOL}	50/60 Hz, RMS, 1 minute	2500	V~	
F_c	Mounting force	22..130/5..29	N/lb	
Weight		5	g	

Symbol	Test Conditions ($T_J = 25^\circ\text{C}$, unless otherwise specified)	Characteristic Values		
		Min.	Typ.	Max.
BV_{DSS}	$V_{GS} = 0\text{ V}$, $I_D = 250\text{ }\mu\text{A}$	300		V
$V_{GS(th)}$	$V_{DS} = V_{GS}$, $I_D = 4\text{ mA}$	2.5		V
I_{GSS}	$V_{GS} = \pm 20\text{ V}_{DC}$, $V_{DS} = 0$		±200	nA
I_{DSS}	$V_{DS} = V_{DSS}$ $V_{GS} = 0\text{ V}$		25 250	μA
$R_{DS(on)}$	$V_{GS} = 10\text{ V}$, $I_D = 51\text{ A}$ Pulse test, $t \leq 300\text{ }\mu\text{s}$, duty cycle $d \leq 2\%$		36	mΩ

ISOPLUS247 (IXFR)
E153432



G = Gate D = Drain
S = Source

Features

- ¹ Silicon chip on Direct-Copper-Bond substrate
 - High power dissipation
 - Isolated mounting surface
 - 2500V electrical isolation
- ¹ International standard packages
- ¹ Unclamped Inductive Switching (UIS) rated
- ¹ Low package inductance
 - easy to drive and to protect

Advantages

- ¹ Easy to mount
- ¹ Space savings
- ¹ High power density

Symbol Test Conditions

Characteristic Values

(T_J = 25°C, unless otherwise specified)

Min. Typ. Max.

g_{fs}	V _{DS} = 10 V; I _D = 51 A, pulse test	45	57	S
C_{iss} C_{oss} C_{rss}	V _{GS} = 0 V, V _{DS} = 25 V, f = 1 MHz	7500	pF	
		1150	pF	
		230	pF	
t_{d(on)} t_r t_{d(off)} t_f	V _{GS} = 10 V, V _{DS} = 0.5 V _{DSS} , I _D = 51 A R _G = 3.3 Ω (External)	30	ns	
		28	ns	
		130	ns	
		30	ns	
Q_{g(on)} Q_{gs} Q_{gd}	V _{GS} = 10 V, V _{DS} = 0.5 V _{DSS} , I _D = 51 A	224	nC	
		50	nC	
		110	nC	
R_{thJC}			0.5	°C/W
R_{thcs}		0.15		°C/W

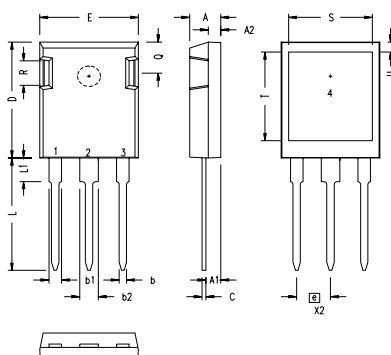
Source-Drain Diode

Characteristic Values

(T_J = 25°C, unless otherwise specified)

Symbol	Test Conditions	Min.	Typ.	Max.
I_s	V _{GS} = 0 V			102 A
I_{SM}	Repetitive			250 A
V_{SD}	I _F = I _s , V _{GS} = 0 V, Pulse test, t ≤ 300 μs, duty cycle d ≤ 2 %			1.5 V
t_{rr} Q_{RM} I_{RM}	I _F = 25 A, -di/dt = 100 A/μs V _R = 100 V, V _{GS} = 0 V		200	ns
		0.8		μC
		7		A

ISOPLUS247 Outline

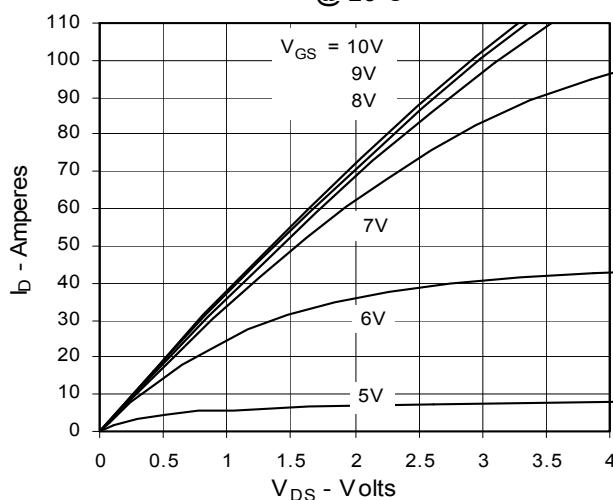


SYM	INCHES		MILLIMETERS	
	MIN	MAX	MIN	MAX
A	.190	.205	4.83	5.21
A1	.090	.100	2.29	2.54
A2	.075	.085	1.91	2.16
b	.045	.055	1.14	1.40
b1	.075	.084	1.91	2.13
b2	.115	.123	2.92	3.12
C	.024	.031	0.61	0.80
D	.819	.840	20.80	21.34
E	.620	.635	15.75	16.13
e	.215	BSC	5.45	BSC
L	.780	.800	19.81	20.32
L1	.150	.170	3.81	4.32
Q	.220	.244	5.59	6.20
R	.170	.190	4.32	4.83
S	.520	.540	13.21	13.72
T	.620	.640	15.75	16.26
U	.065	.080	1.65	2.03

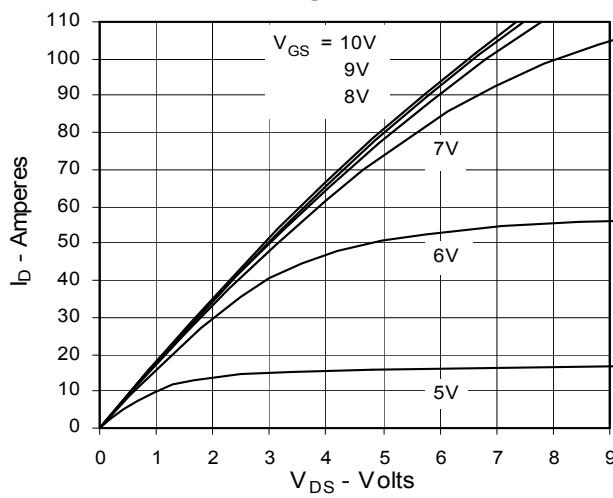
1 – GATE
2 – DRAIN (COLLECTOR)
3 – SOURCE (EMITTER)
4 – NO CONNECTION

NOTE: This drawing will meet all dimensions requirement of JEDEC outline TO-247AD except screw hole.

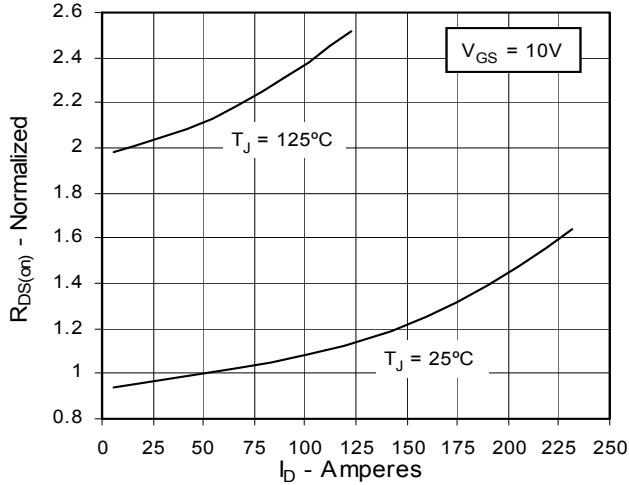
**Fig. 1. Output Characteristics
@ 25°C**



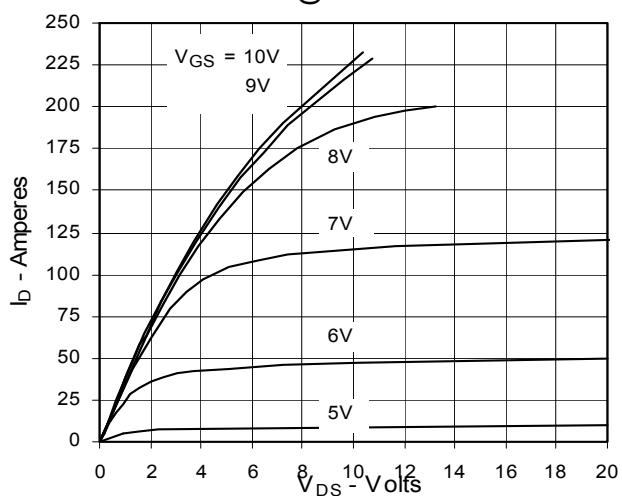
**Fig. 3. Output Characteristics
@ 125°C**



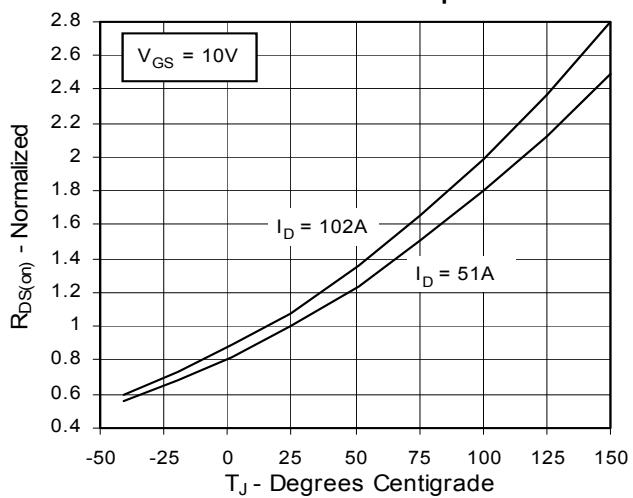
**Fig. 5. $R_{DS(on)}$ Normalized to
 $I_D = 51A$ Value vs. Drain Current**



**Fig. 2. Extended Output Characteristics
@ 25°C**



**Fig. 4. $R_{DS(on)}$ Normalized to $I_D = 51A$
Value vs. Junction Temperature**



**Fig. 6. Drain Current vs. Case
Temperature**

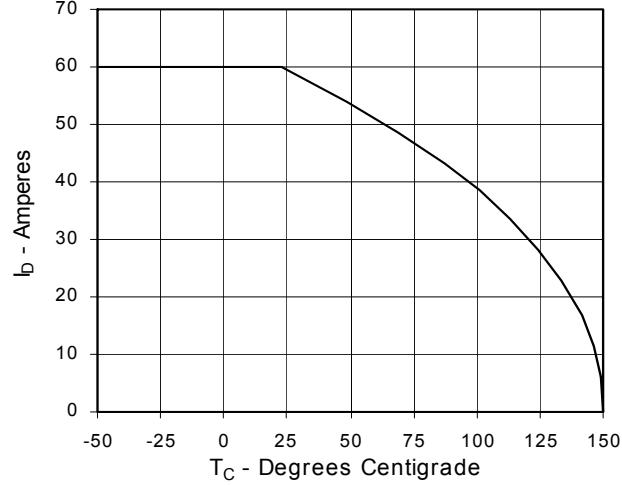


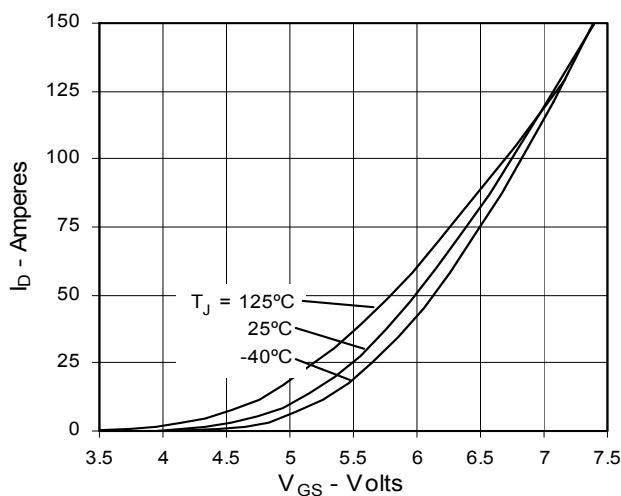
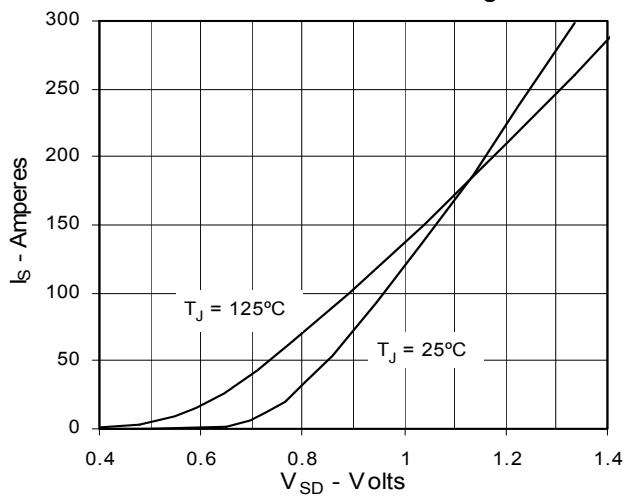
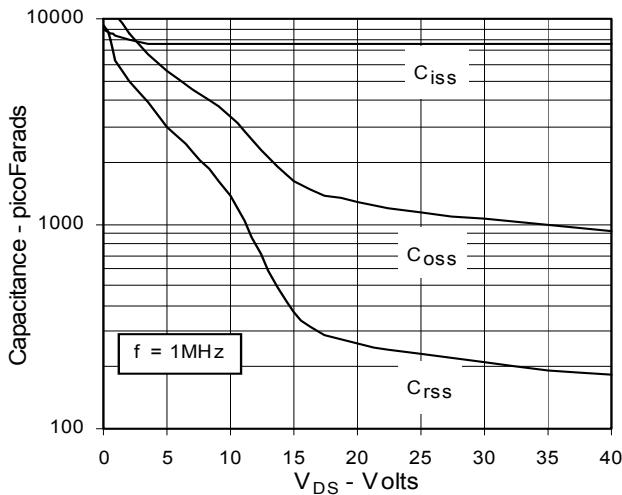
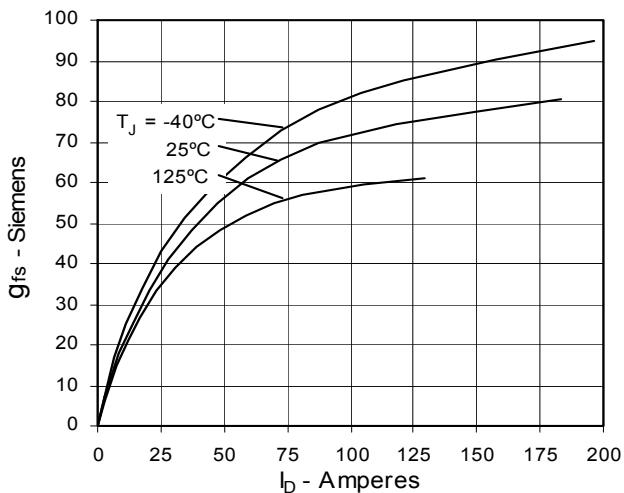
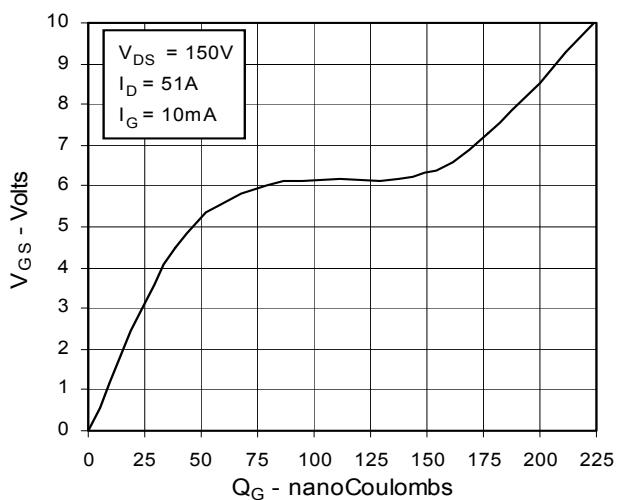
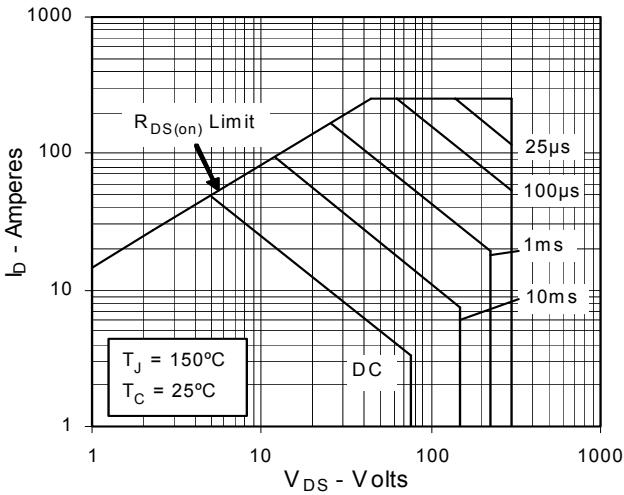
Fig. 7. Input Admittance**Fig. 9. Source Current vs. Source-To-Drain Voltage****Fig. 11. Capacitance****Fig. 8. Transconductance****Fig. 10. Gate Charge****Fig. 12. Forward-Bias Safe Operating Area**

Fig. 13. Maximum Transient Thermal Resistance